N-channel LFPAK 80 V 8.5 m Ω standard level MOSFET

Rev. 01 — 25 June 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel MOSFET in LFPAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power converters
- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package

1.3 Applications

- DC-to-DC converters
- Lithium-ion battery protection
- Load switching

- Motor control
- Server power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	-	80	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	-	-	82	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	130	W
T_j	junction temperature		-55	-	175	°C
Avalance	he ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 75 A; V_{sup} ≤ 80 V; R_{GS} = 50 Ω; unclamped	-	-	120	mJ
Dynamic	Dynamic characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$	-	12	-	nC
$Q_{G(tot)}$	total gate charge	V _{DS} = 40 V; see <u>Figure 14;</u> see <u>Figure 15</u>	-	55	-	nC



Table 1. Quick reference ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 100 \text{ °C}; \text{ see } \frac{\text{Figure 12}}{}$	-	-	13.4	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 12}{\text{Figure } 12};$	-	5.8	8.5	mΩ

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		
4	G	gate	9	
mb D	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

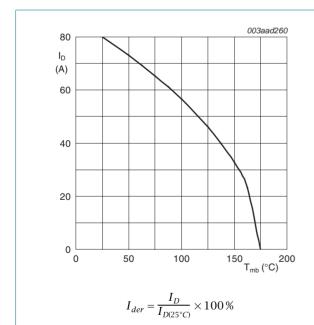
Type number	Package	Package							
	Name	Description	Version						
PSMN8R2-80YS	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669						

Limiting values

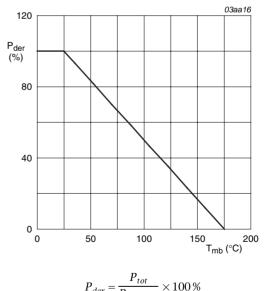
Limiting values Table 4.

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	80	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	80	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	-	57	А
		$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{}$	-	82	Α
I_{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	326	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	130	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
$T_{sld(M)}$	peak soldering temperature		-	260	°C
Source-dra	ain diode				
Is	source current	T _{mb} = 25 °C	-	82	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	326	А
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 75 A; V_{sup} ≤ 80 V; R_{GS} = 50 Ω; unclamped	-	120	mJ



Normalized continuous drain current as a function of mounting base temperature



 $P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$

Fig 2. Normalized total power dissipation as a function of mounting base temperature

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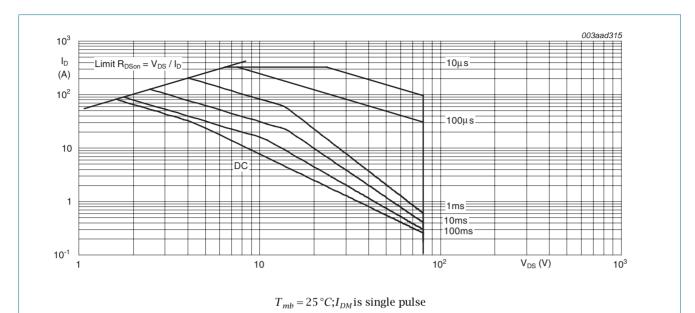
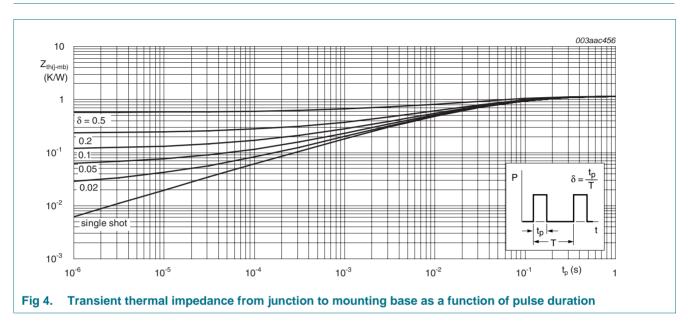


Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	1.1	K/W



6. Characteristics

Table 6. Characteristics

le 6.	Characteristics					
nbol	Parameter	Conditions	Min	Тур	Max	Unit
tic char	racteristics					
R)DSS	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	73	-	-	V
	breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	80	-	-	V
6(th)	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 175$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	1	-	-	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	-	4.6	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	2	3	4	V
3	drain leakage current	$V_{DS} = 80 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	4	μΑ
		V _{DS} = 80 V; V _{GS} = 0 V; T _j = 125 °C	-	-	50	μΑ
3	gate leakage current	$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
		V _{GS} = 20 V; V _{DS} = 0 V; T _j = 25 °C	-	-	100	nΑ
R _{DSon} drain-source on-state resistance		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see Figure 12	-	-	20	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 100 \text{ °C};$ see Figure 12	-	-	13.4	mΩ
		V_{GS} = 10 V; I_D = 15 A; T_j = 25 °C; see <u>Figure 13</u> ; see <u>Figure 12</u>	-	5.8	8.5	mΩ
	internal gate resistance (AC)	f = 1 MHz	-	0.74	-	Ω
iamic cl	haracteristics					
tot)	total gate charge	$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}$	-	48	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V};$	-	55	-	nC
6	gate-source charge	see Figure 14; see Figure 15	-	15	-	nC
S(th)	pre-threshold gate-source charge	$I_D = 25 \text{ A}$; $V_{DS} = 40 \text{ V}$; $V_{GS} = 10 \text{ V}$; see Figure 14	-	10	-	nC
S(th-pl)	post-threshold gate-source charge		-	5	-	nC
)	gate-drain charge	$I_D = 25 \text{ A}$; $V_{DS} = 40 \text{ V}$; $V_{GS} = 10 \text{ V}$; see Figure 14; see Figure 15	-	12	-	nC
S(pl)	gate-source plateau voltage	$I_D = 25 \text{ A}$; $V_{DS} = 40 \text{ V}$; see <u>Figure 15</u> ; see <u>Figure 14</u>	-	4.5	-	V
	input capacitance	V _{DS} = 40 V; V _{GS} = 0 V; f = 1 MHz;	-	3640	-	pF
S	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	390	-	pF
i	reverse transfer capacitance		-	180	-	pF
1)	turn-on delay time	$V_{DS} = 40 \text{ V}; R_L = 1.6 \Omega; V_{GS} = 10 \text{ V};$	-	25	-	ns
	rise time	$R_{G(ext)} = 4.7 \Omega$	-	22	-	ns
f)	turn-off delay time		-	51	-	ns
	fall time		-	16	-	ns
	capacitance turn-on delay time rise time turn-off delay time			25 22 51	- - -	

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Characteristics ... continued Table 6.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 17</u>	-	0.81	1.2	V
t _{rr}	reverse recovery time	$I_S = 50 \text{ A}$; $dI_S/dt = 100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	55	-	ns
Q _r	recovered charge	$V_{DS} = 40 \text{ V}$	-	106	-	nC

[1] Tested to JEDEC standards where applicable.

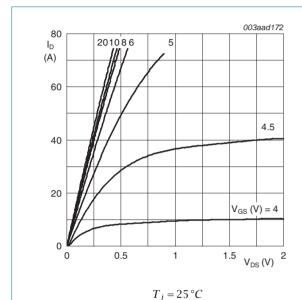
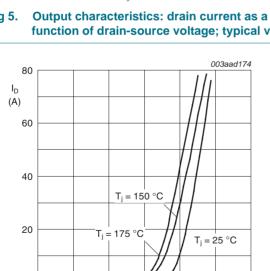


Fig 5. function of drain-source voltage; typical values



 $V_{DS} > I_D \times R_{DSon}$ Transfer characteristics: drain current as a Fig 7.

function of gate-source voltage; typical values

2

V_{GS} (V)

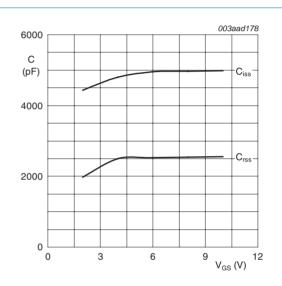
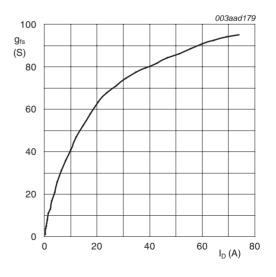


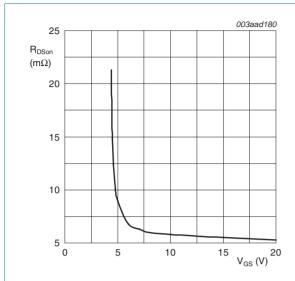
Fig 6. Input and reverse transfer capacitances as a function of gate-source voltage; typical values

 $V_{DS} = 0V; f = 1MHz$



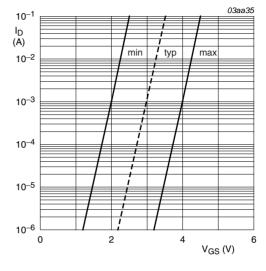
 $T_i = 25 \,^{\circ}C; V_{DS} = 25 V$

Fig 8. Forward transconductance as a function of drain current; typical values



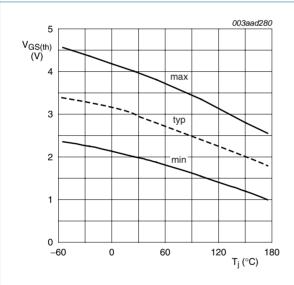
Drain-source on-state resistance as a function Fig 9. of gate-source voltage; typical values

 $T_j = 25 \,^{\circ}C; I_D = 25A$



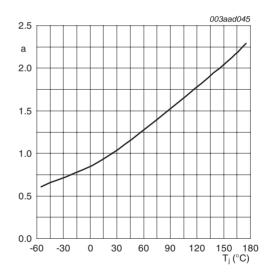
 $T_{j} = 25 \,^{\circ}C; V_{DS} = 5V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



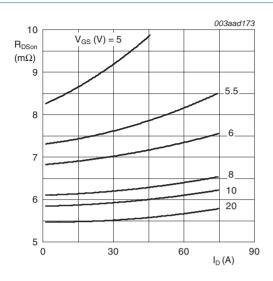
 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 11. Gate-source threshold voltage as a function of junction temperature



 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$

Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature



 $T_j = 25 \,^{\circ}C$

Fig 13. Drain-source on-state resistance as a function of drain current; typical values

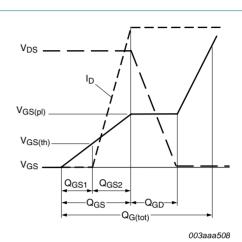
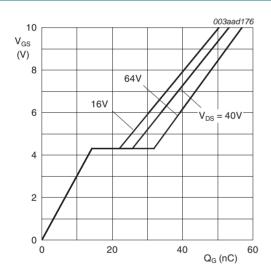
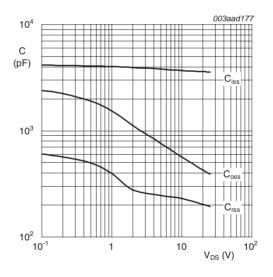


Fig 14. Gate charge waveform definitions



 $T_j = 25 \,^{\circ}C; I_D = 25A$

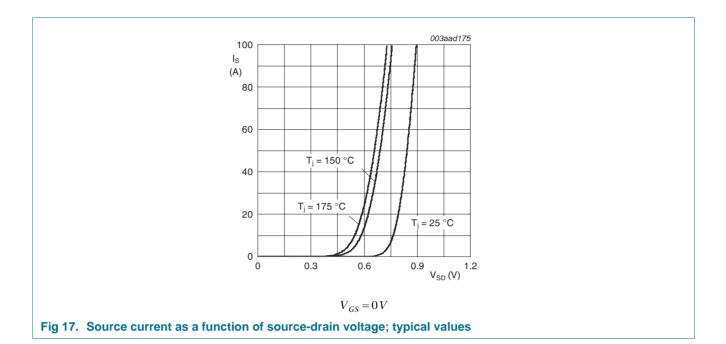
Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0 \, V; f = 1 MHz$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

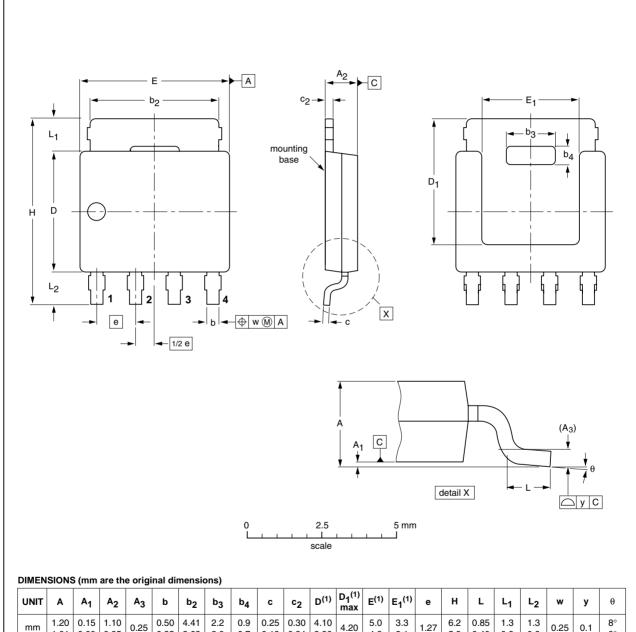
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Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



UNIT	Α	A ₁	A ₂	A ₃	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19		4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT669		MO-235				04-10-13 06-03-16

Fig 18. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN8R2-80YS	20090625	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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